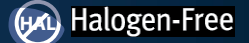


EPC2066 – Enhancement Mode Power Transistor

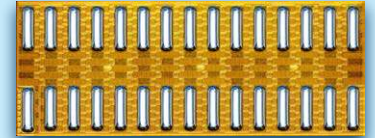
 $V_{DS}, 40\text{ V}$
 $R_{DS(on)}, 1.1\text{ m}\Omega\text{ max}$
 $I_D, 90\text{ A}$


Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Questions:



6.05 x 2.3 mm

EPC2066 eGaN® FETs are supplied in passivated die form with solder bumps.

Maximum Ratings

PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	
I_D	Continuous ($T_A = 25^\circ\text{C}$)	90	A
	Pulsed (25°C, $T_{PULSE} = 300\ \mu\text{s}$)	639	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	°C
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Case TOP)	0.3	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board (Case BOTTOM)	1.0	
$R_{\theta JA_JEDEC}$	Thermal Resistance, Junction-to-Ambient (using JEDEC 51-2 PCB)	51	
$R_{\theta JA_EVB}$	Thermal Resistance, Junction-to-Ambient (using EPC90122 EVB)	29	

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}, I_D = 1.2\text{ mA}$	40			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 0\text{ V}, V_{DS} = 32\text{ V}$		0.006	1.0	mA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$		0.006	4.0	
	Gate-to-Source Forward Leakage [#]	$V_{GS} = 5\text{ V}, T_J = 125^\circ\text{C}$		0.2	9.0	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$		0.007	0.3	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 28\text{ mA}$	0.7	1.2	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}, I_D = 50\text{ A}$		0.8	1.1	mΩ
V_{SD}	Source-Drain Forward Voltage [#]	$I_S = 0.5\text{ A}, V_{GS} = 0\text{ V}$		1.5		V

[#] Defined by design. Not subject to production test.

Applications

- High Density DC-DC Conversion
- Motor Drive
- Industrial Automation
- Synchronous Rectification
- Inrush Protection
- Point-of-Load (POL) Converters

Benefits

- Ultra High Efficiency
- Higher Switching Frequency
- Very Low $R_{DS(on)}$, Q_G , Q_{GD} , Q_{OSS} and 0 Q_{RR}
- Small Footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://l.ead.me/EPC2066>

Dynamic Characteristics# (T_J = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance	V _{DS} = 20 V, V _{GS} = 0 V		3539	4523	pF
C _{RSS}	Reverse Transfer Capacitance			30		
C _{OSS}	Output Capacitance			1670	1919	
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 1)	V _{DS} = 0 to 20 V, V _{GS} = 0 V		2431		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 2)			2970		
R _G	Gate Resistance			0.4		Ω
Q _G	Total Gate Charge	V _{DS} = 20 V, V _{GS} = 5 V, I _D = 50 A		25	33	nC
Q _{GS}	Gate to Source Charge	V _{DS} = 20 V, I _D = 50 A		8.9		
Q _{GD}	Gate to Drain Charge			3.2		
Q _{G(TH)}	Gate Charge at Threshold			6.7		
Q _{OSS}	Output Charge	V _{GS} = 0 V, V _{DS} = 20 V		59	78	
Q _{RR}	Source-Drain Recovery Charge			0		

Defined by design. Not subject to production test.

All measurements were done with substrate shorted to source.

Note 1: C_{OSS(ER)} is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Note 2: C_{OSS(TR)} is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 1: Typical Output Characteristics at 25°C

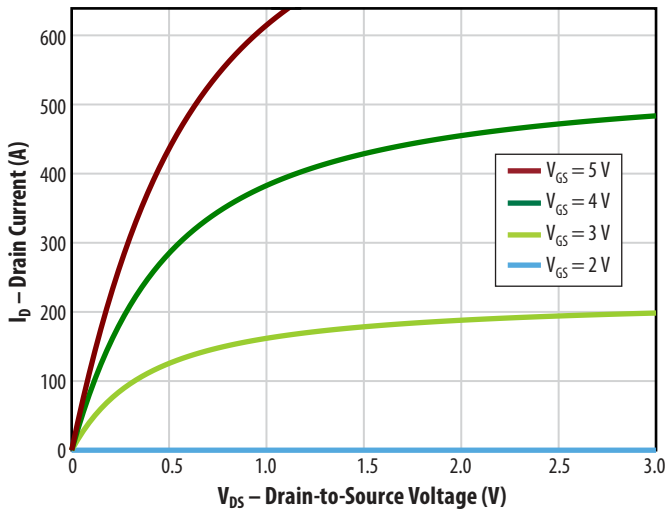


Figure 2: Typical Transfer Characteristics

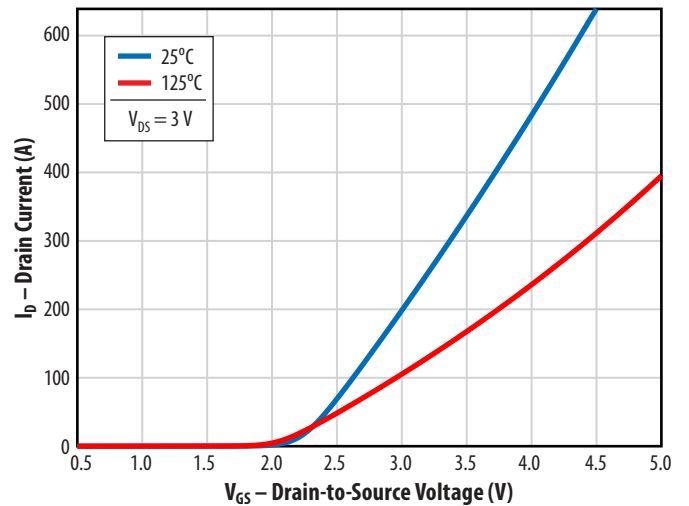


Figure 3: R_{DS(on)} vs. V_{GS} for Various Currents

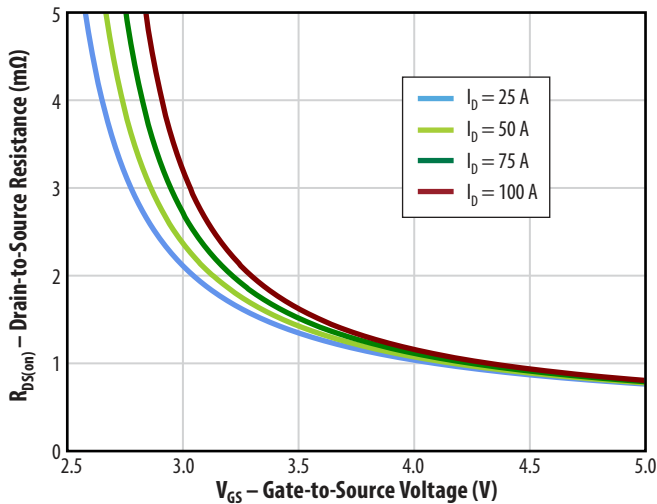


Figure 4: R_{DS(on)} vs. V_{GS} for Various Temperatures

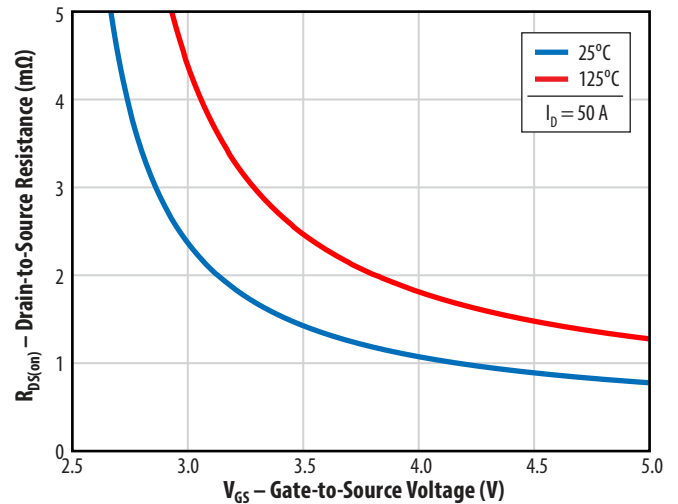


Figure 5a: Typical Capacitance (Linear Scale)

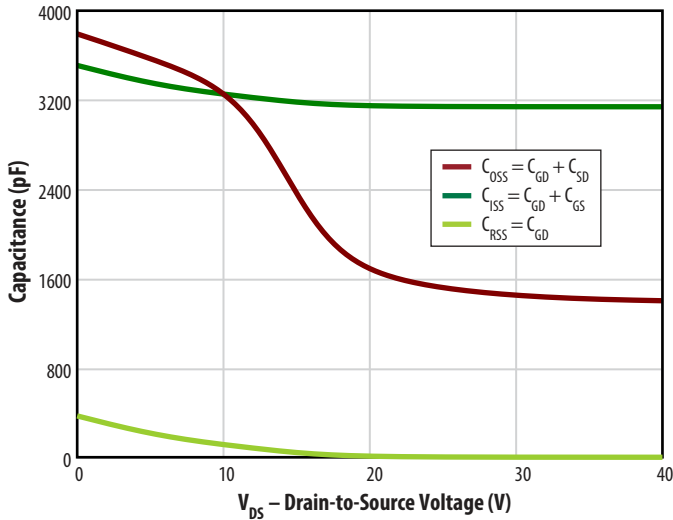


Figure 5b: Typical Capacitance (Log Scale)

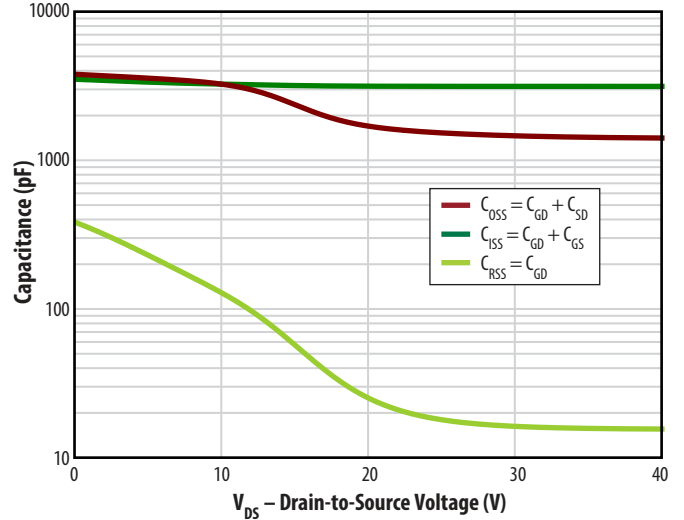


Figure 6: Typical Output Charge and C_{OSS} Stored Energy

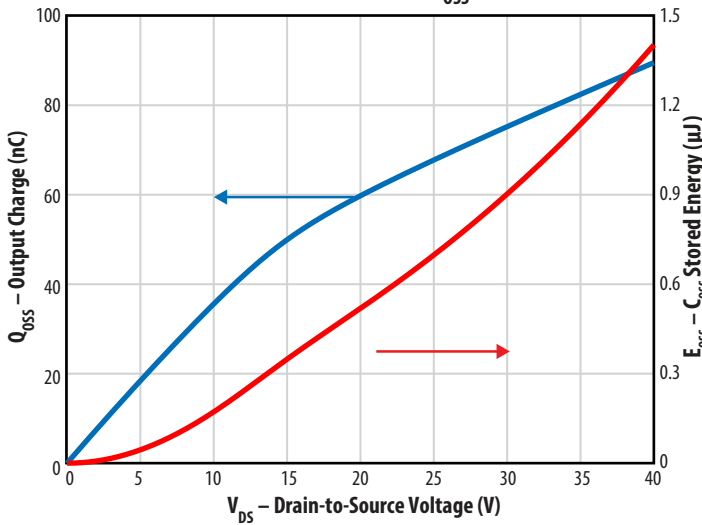


Figure 7: Typical Gate Charge

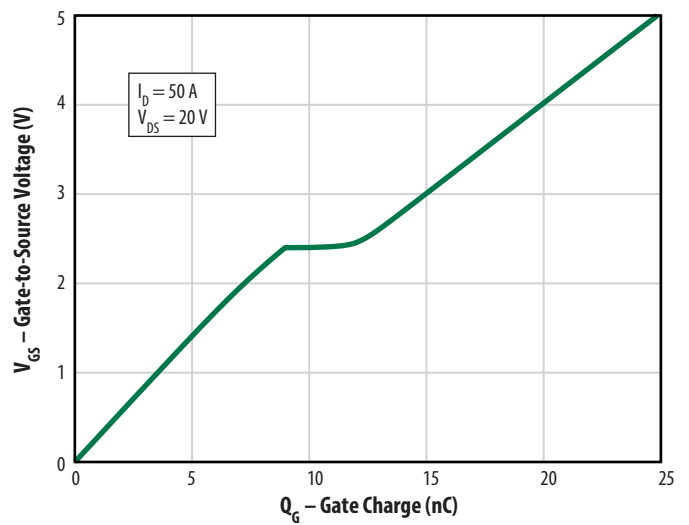


Figure 8: Reverse Drain-Source Characteristics

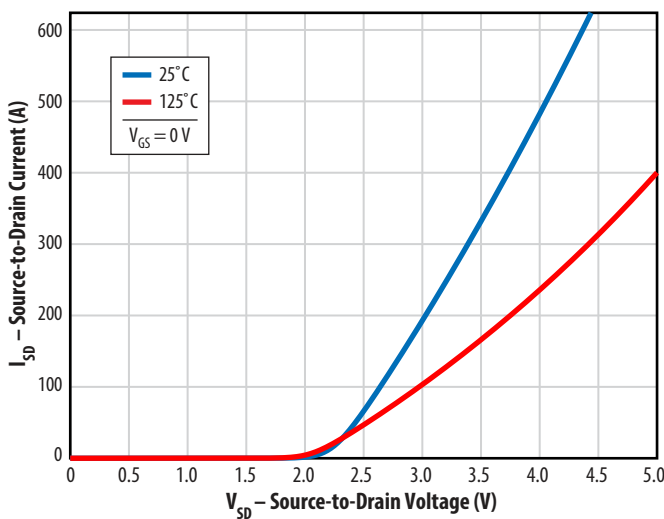
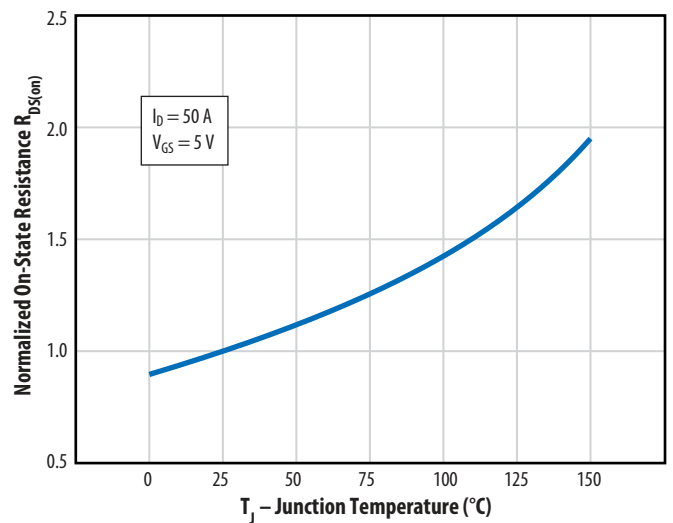


Figure 9: Normalized On-State Resistance vs. Temperature



Note: Negative gate drive voltage increases the reverse drain-source voltage.
EPC recommends 0 V for OFF.

Figure 10: Normalized Threshold Voltage vs. Temperature

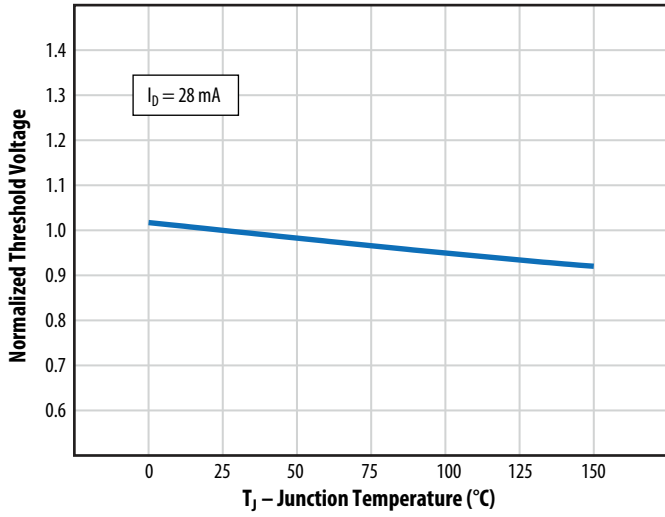


Figure 11: Safe Operating Area

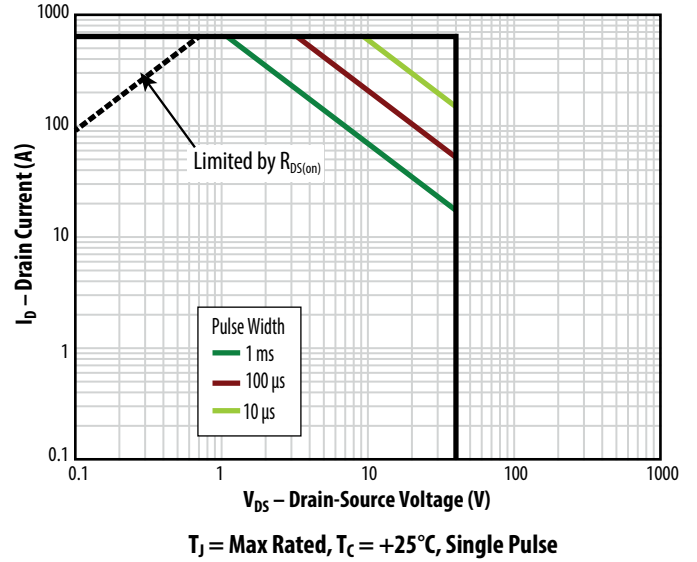
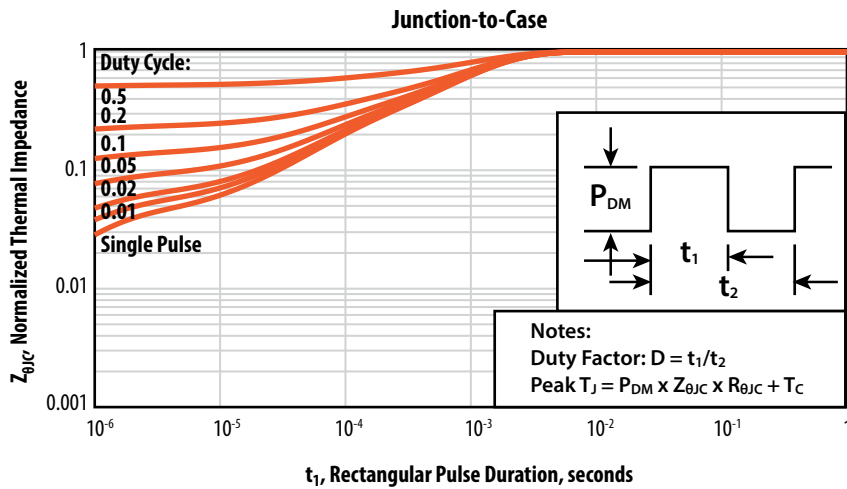
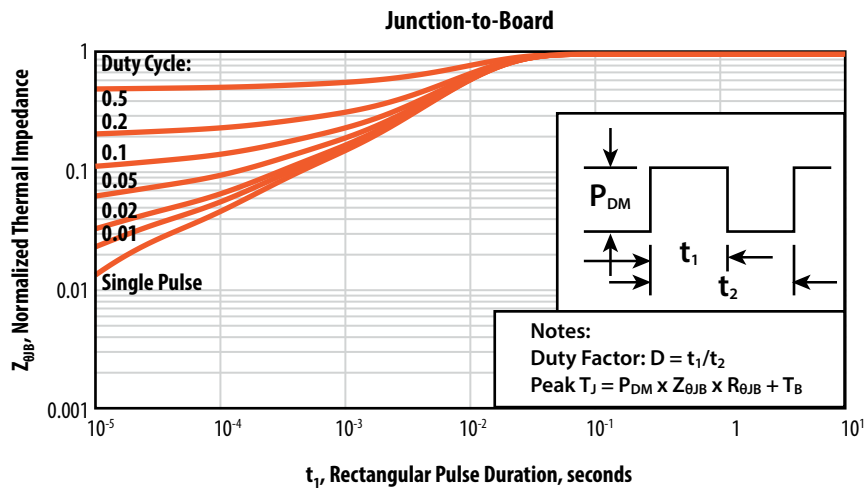
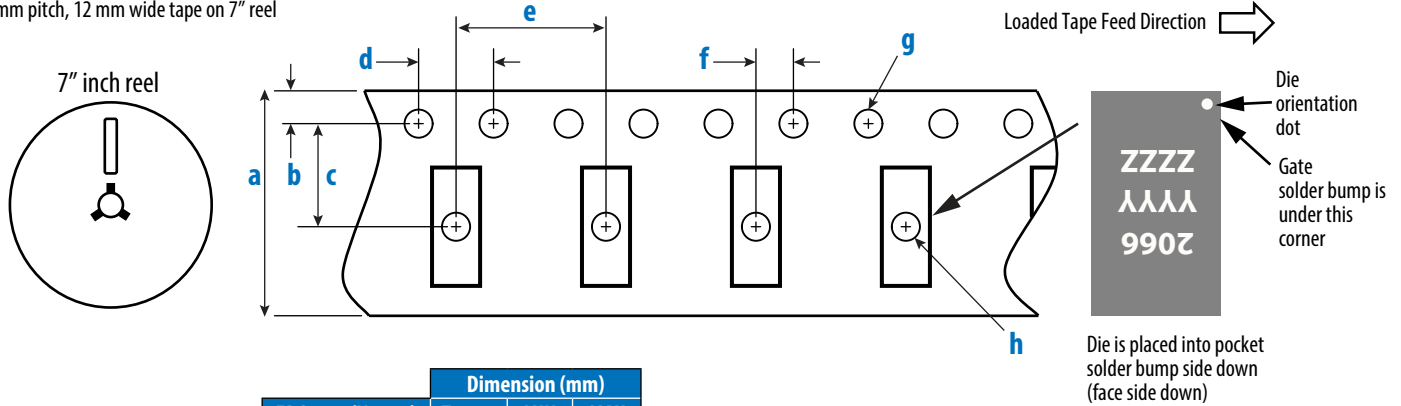


Figure 12: Transient Thermal Response Curves



TAPE AND REEL CONFIGURATION

8 mm pitch, 12 mm wide tape on 7" reel

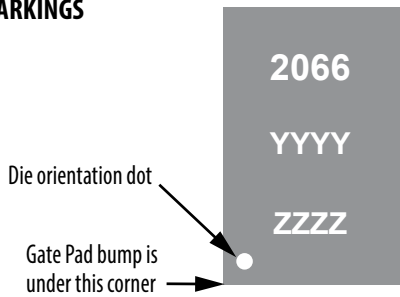


EPC2066 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.50	1.50	1.75

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

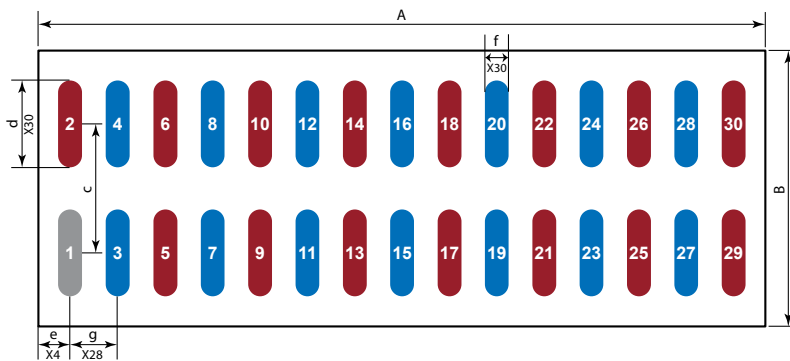
DIE MARKINGS



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2066	2066	YYYY	ZZZZ

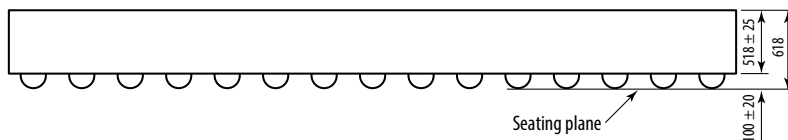
DIE OUTLINE

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
C		1330	
D		720	
E		225	
F		200	
G		400	

Side View



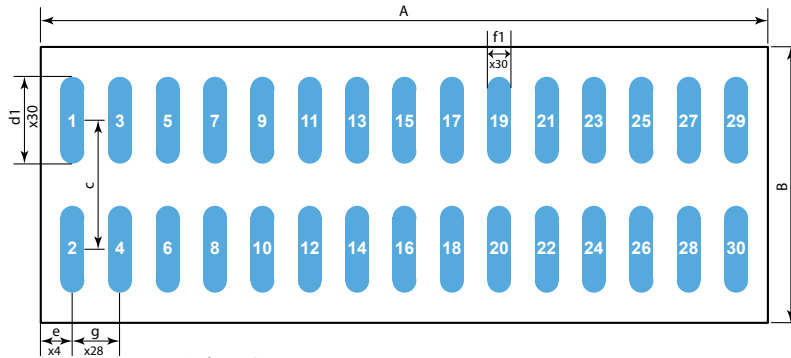
Pad 1 is Gate;

Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29, 30 are Source;

Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain

Note: Substrate (top side) connected to source

RECOMMENDED LAND PATTERN
(units in μm)

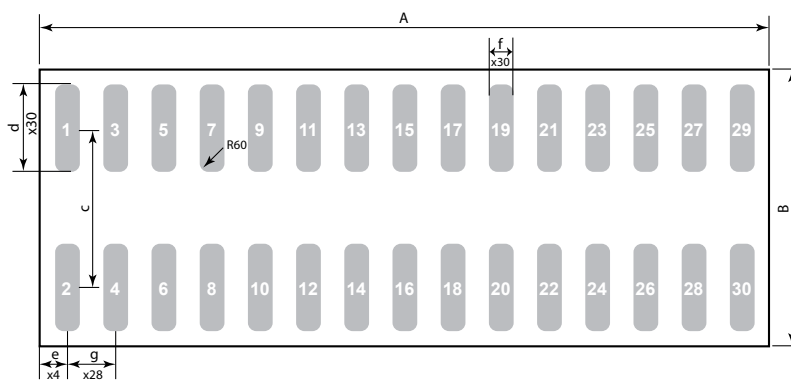


Pad 1 is Gate;
 Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29, 30 are Source;
 Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain

Land pattern is solder mask defined.

DIM	Micrometers
A	6050
B	2300
c	1330
d1	700
e	225
f1	180
g	400

RECOMMENDED STENCIL DRAWING
(units in μm)



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

DIM	Micrometers
A	6050
B	2300
c	1330
d	700
e	225
f	180
g	400

Additional Resources Available

- Assembly resources available at: <https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>
- Library of Altium footprints for production FETs and ICs: <https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip>
(for preliminary device Altium footprints, contact EPC)

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

eGaN® is a registered trademark of Efficient Power Conversion Corporation.
 EPC Patent Listing: epc-co.com/epc/AboutEPC/Patents.aspx

Information subject to change without notice.
 Revised April, 2023